

ALMA MATER STUDIORUM
UNIVERSITÀ DI BOLOGNA



A method to simulate SIC-SFCL in 3D FEM coupled to electrical circuits

Authors/Speaker: **Gabriel dos Santos**, F. Sass, G.G. Sotelo, A. Morandi, F. Grilli



Summary

1. Introduction
2. Methodology
3. Results
4. Conclusion

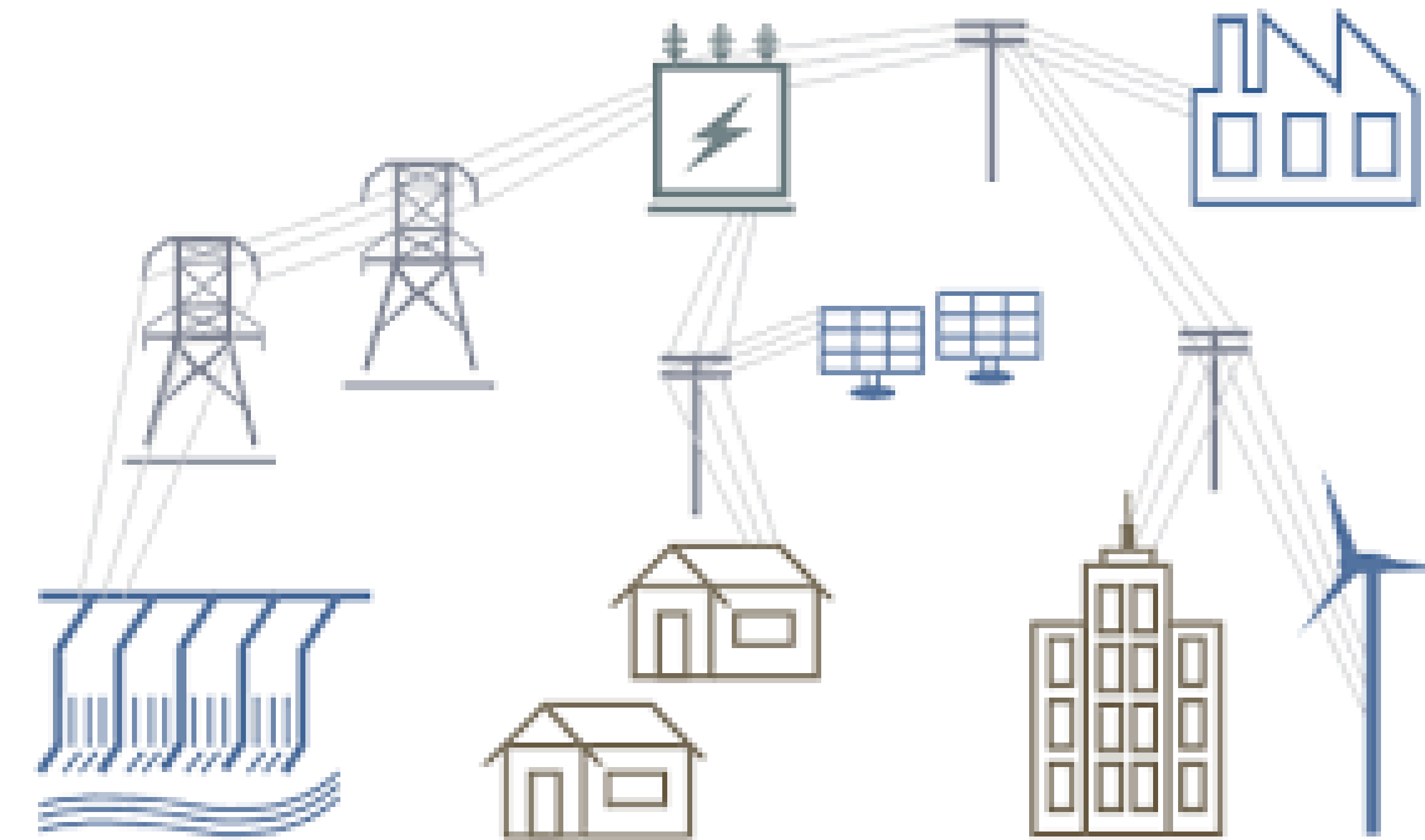
Introduction

Contextualization:

- Load increasing

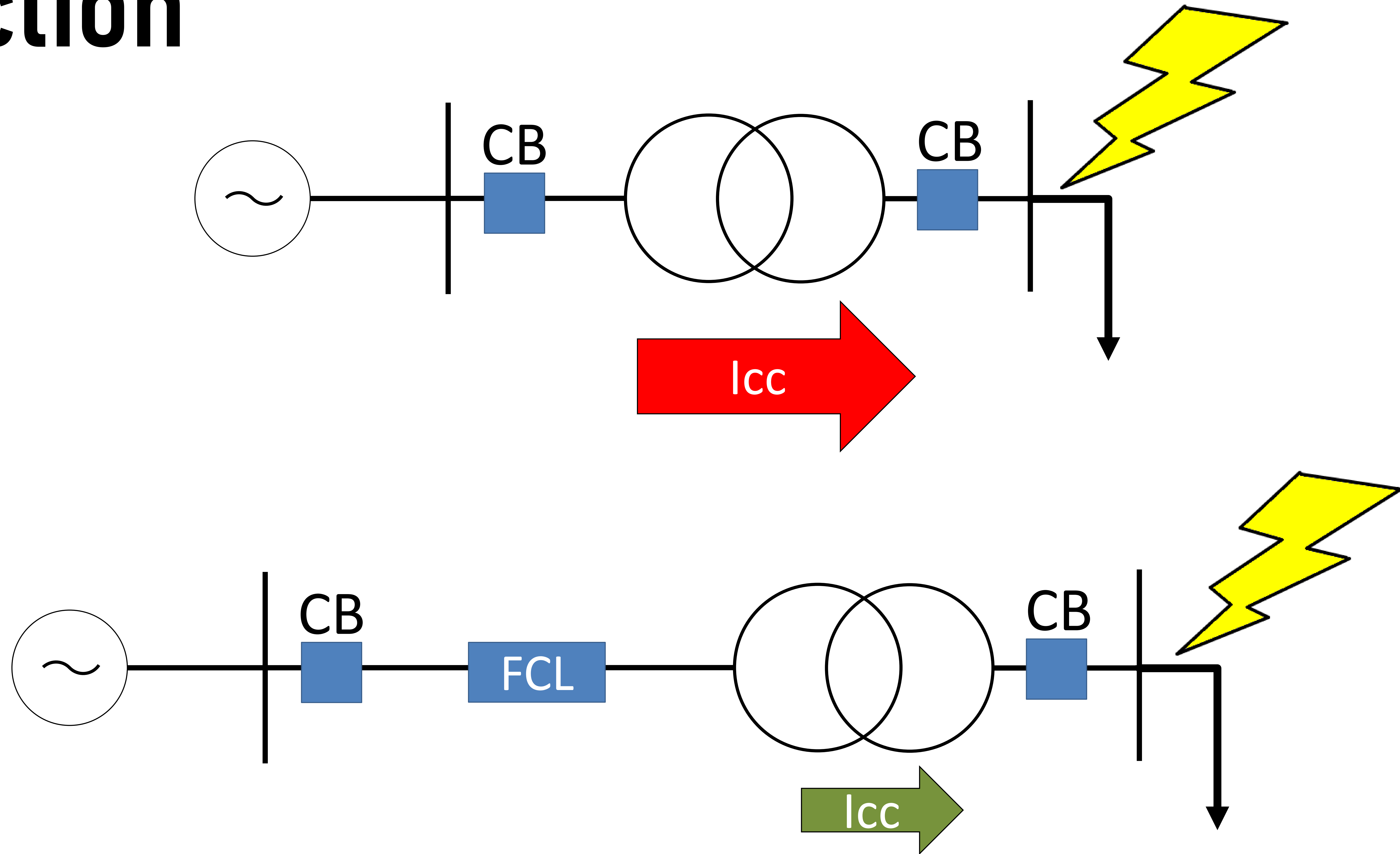


- Distributed Generation Increasing



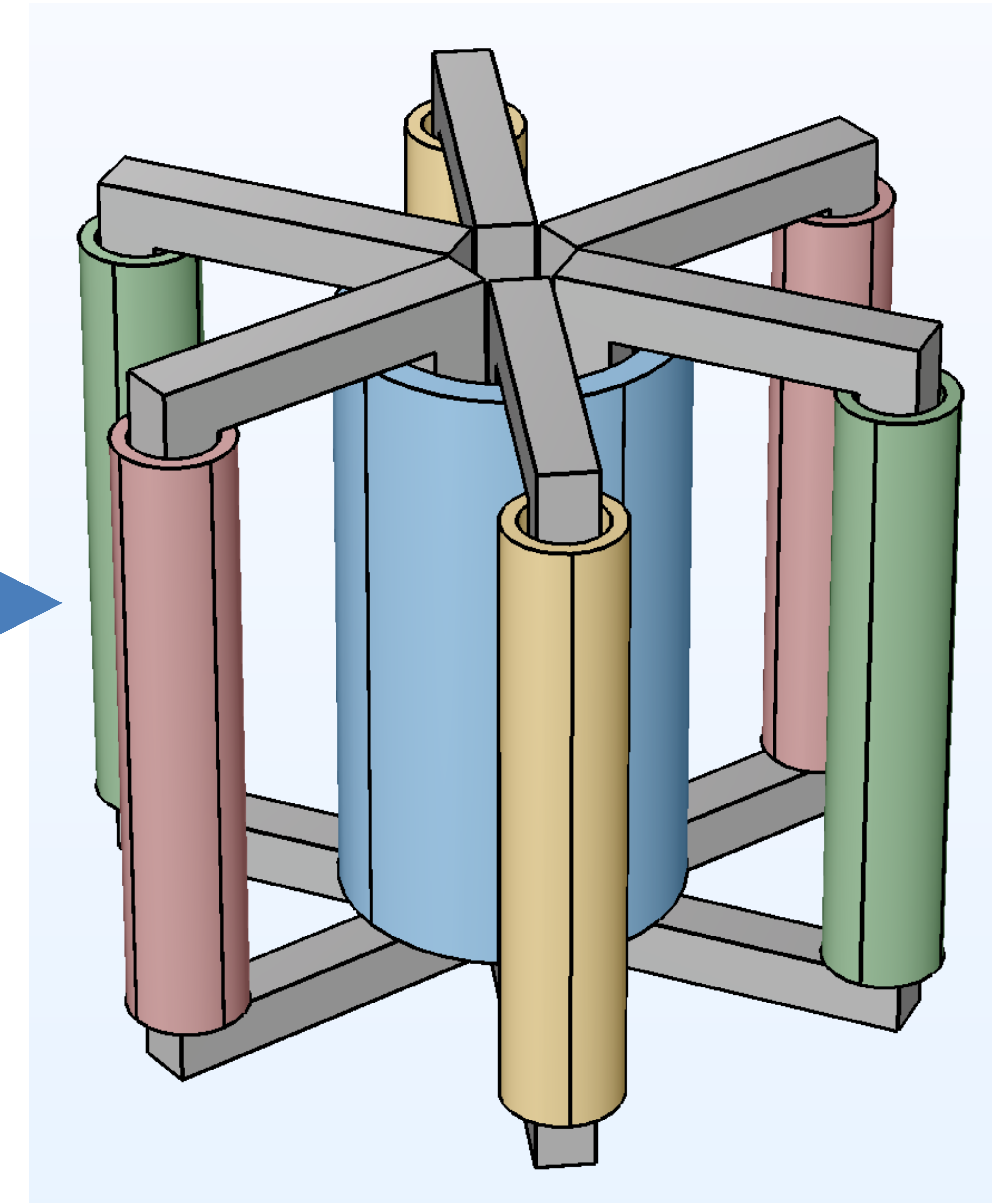
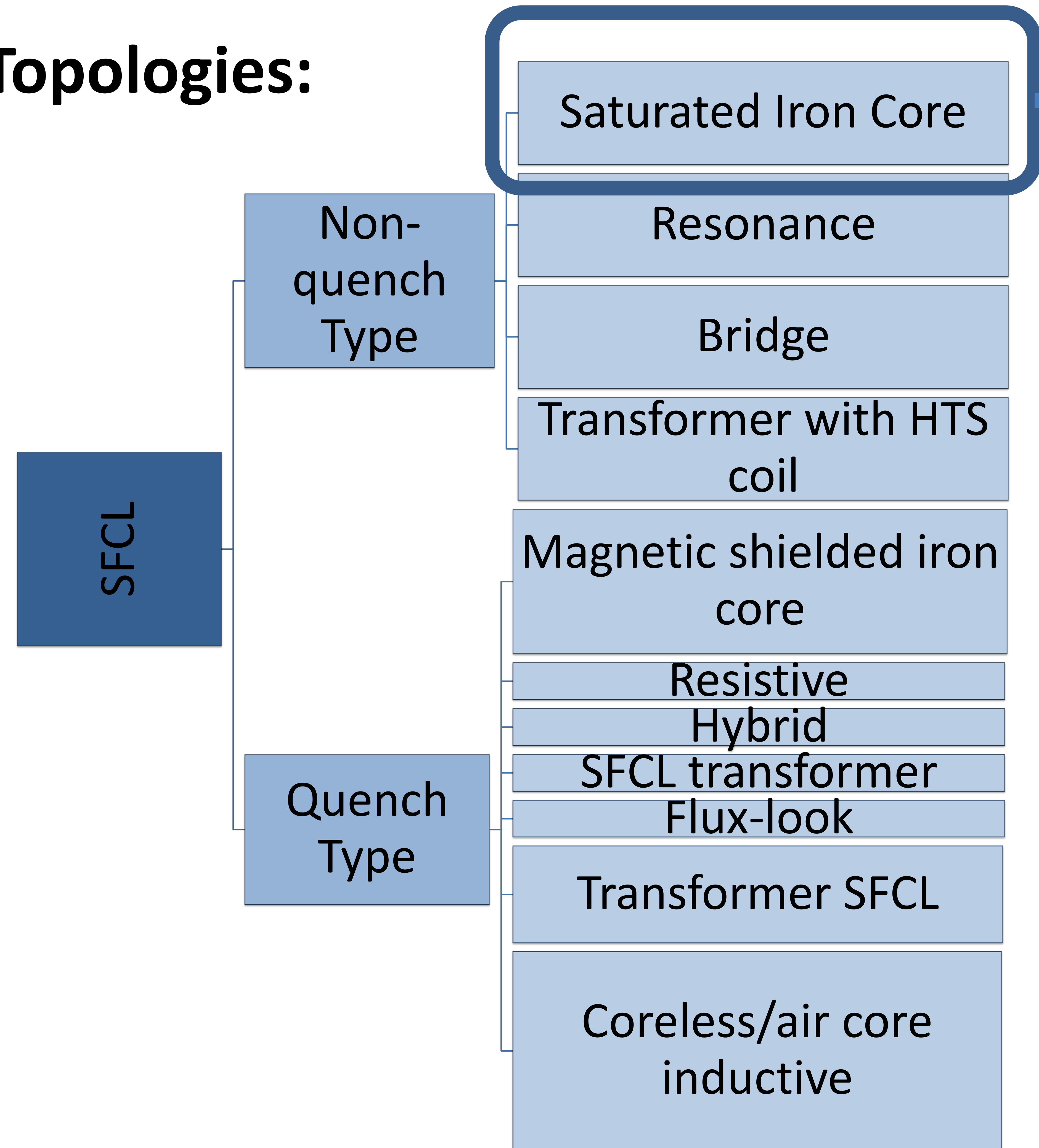
Introduction

Motivations:



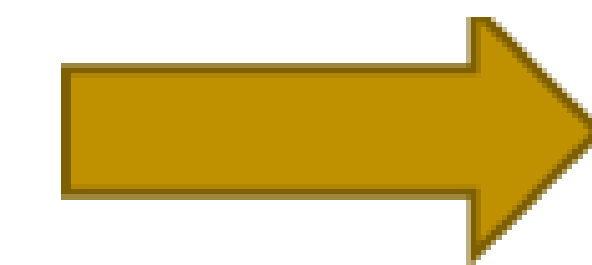
Introduction

Topologies:



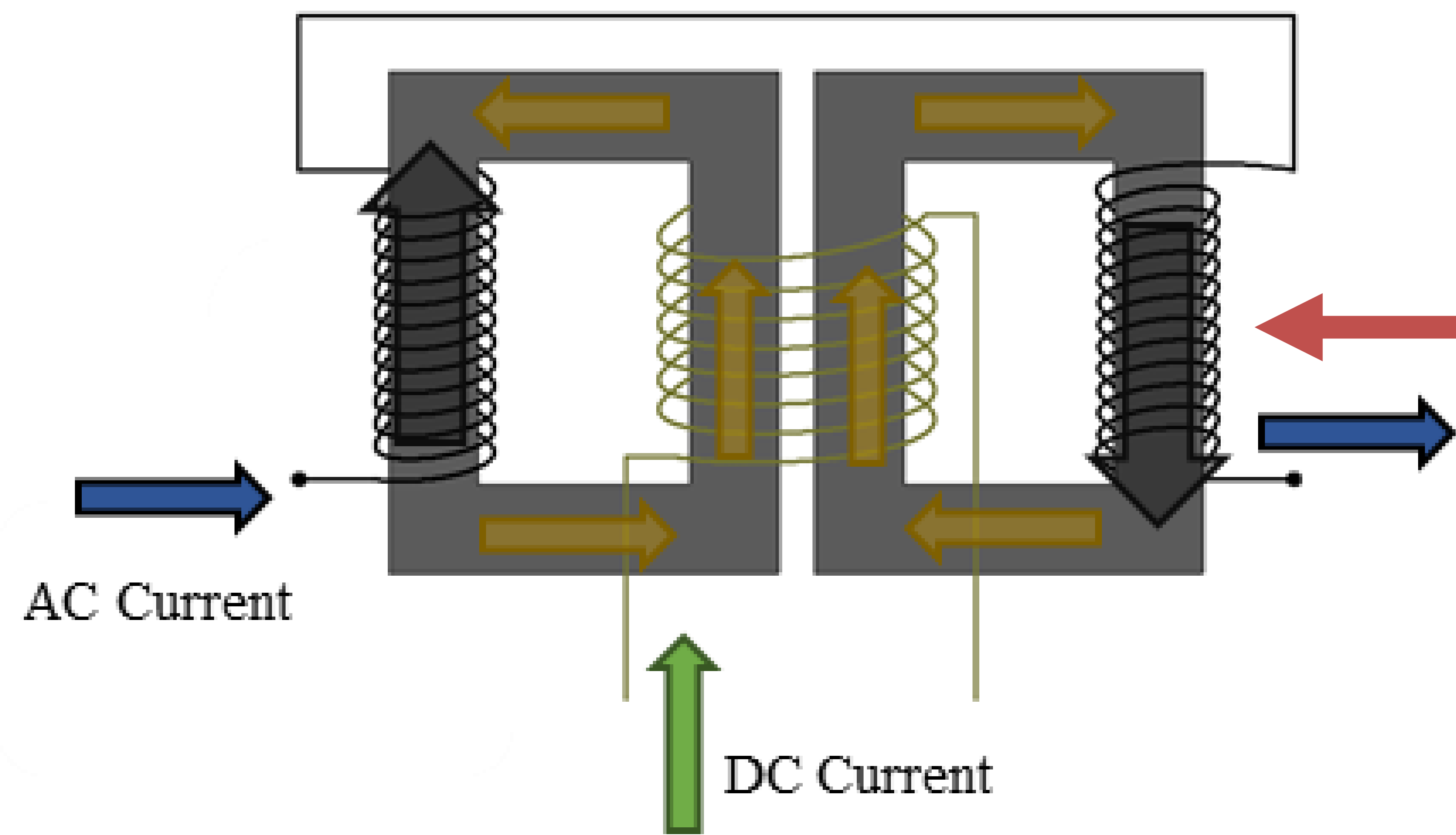
Introduction

Fundamental Principals:

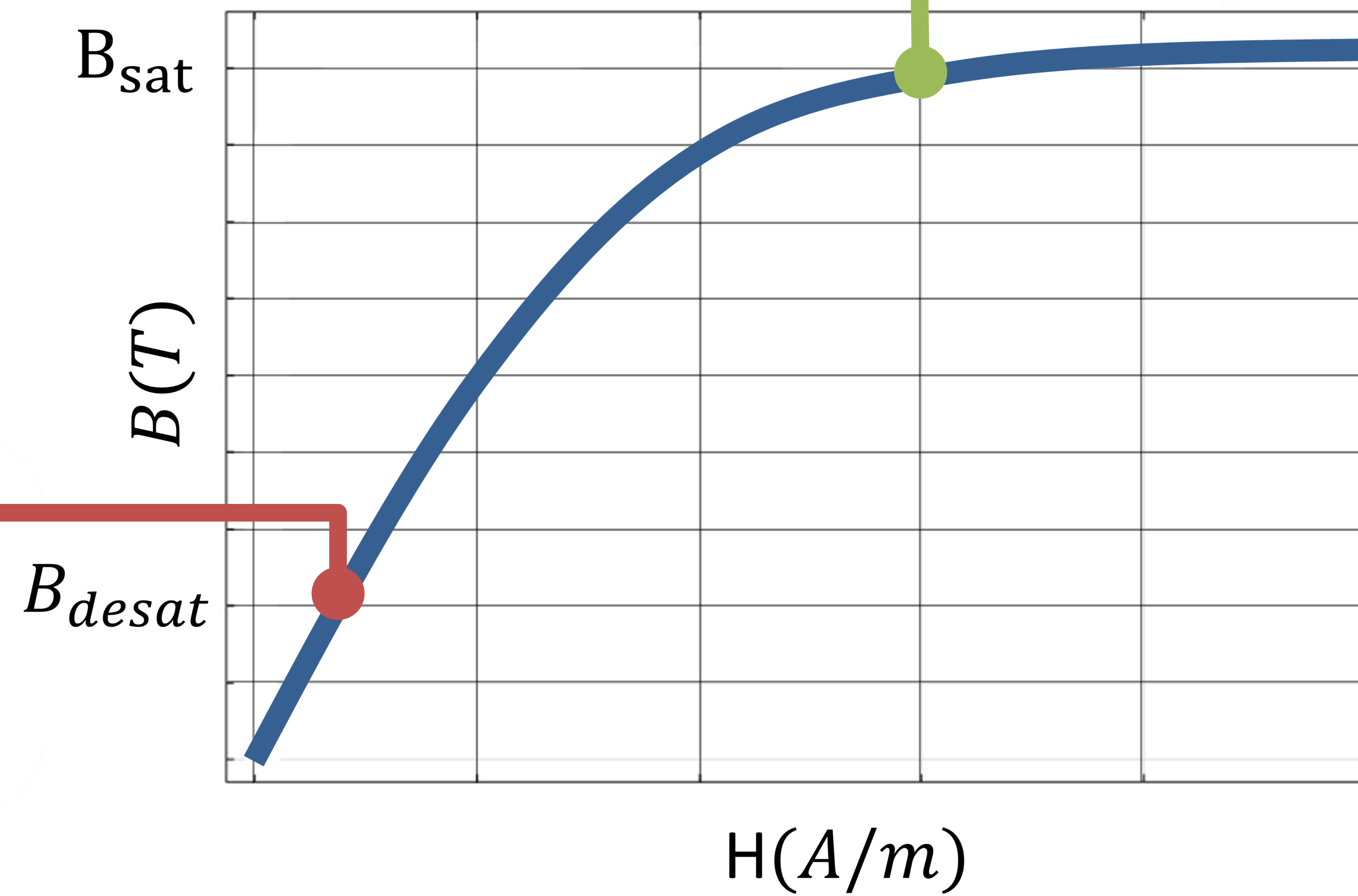
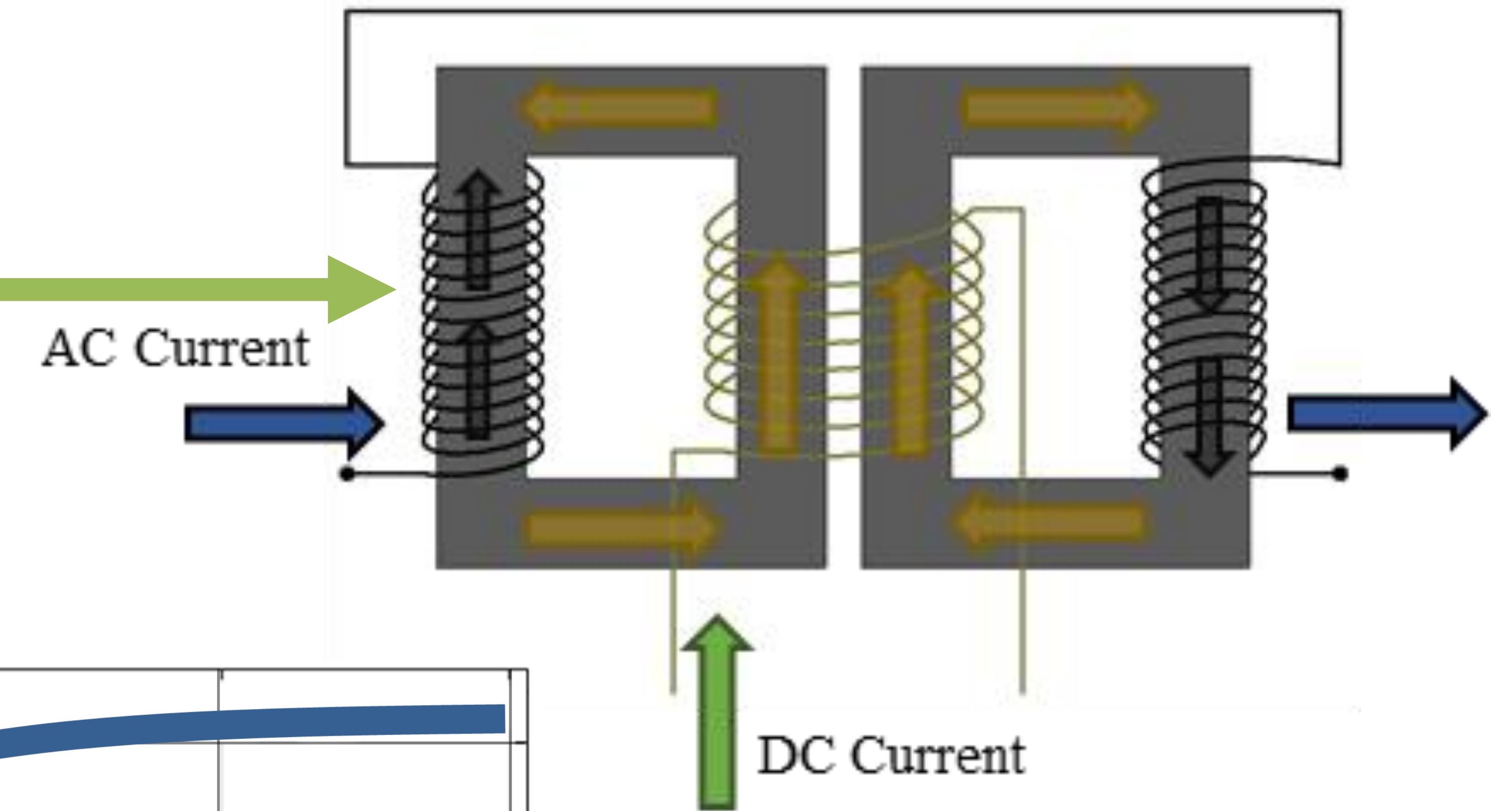
 Magnetic Flux Density due to DC current

 Magnetic Flux Density due to AC current

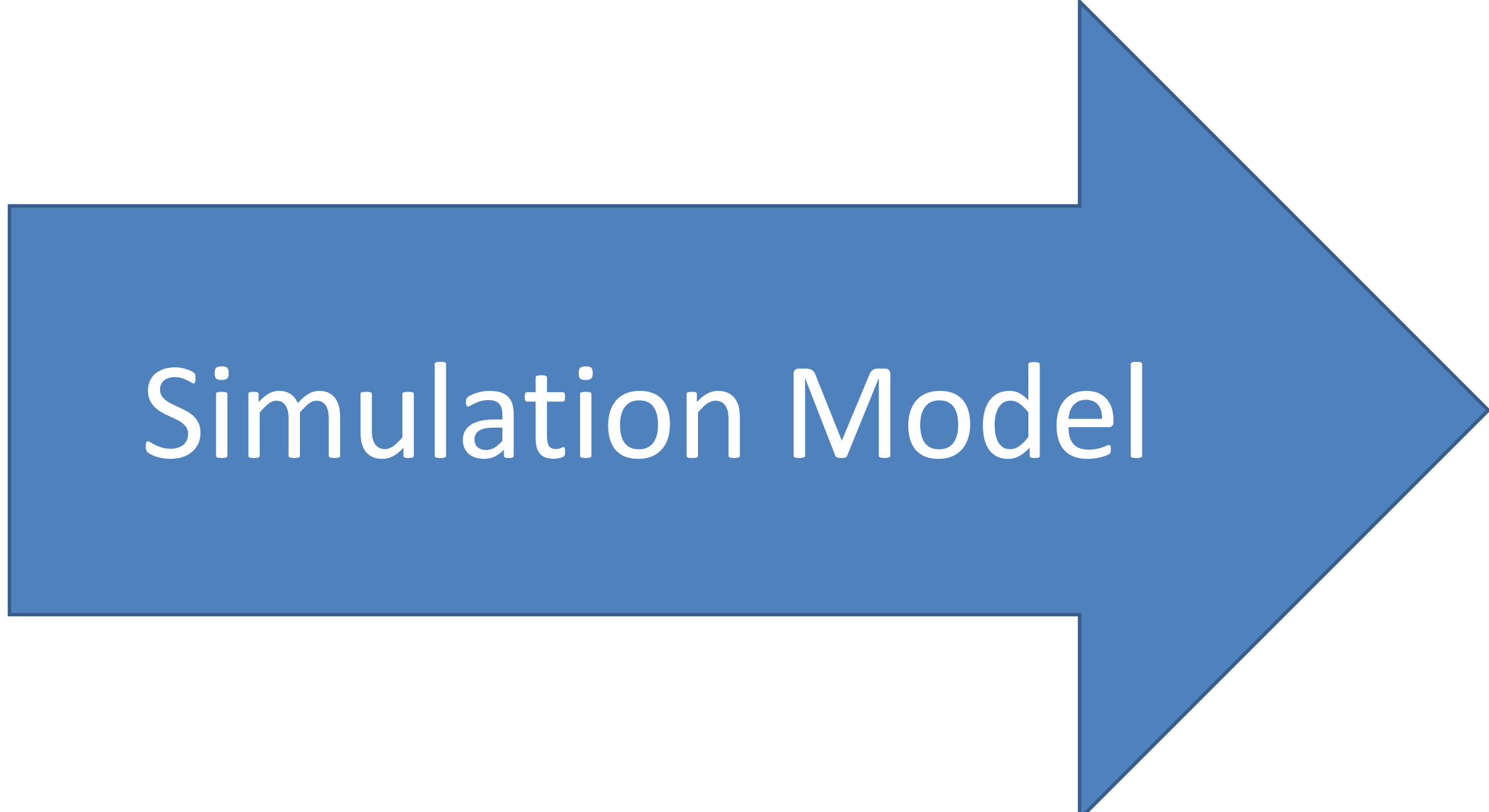
Short-Circuit condition



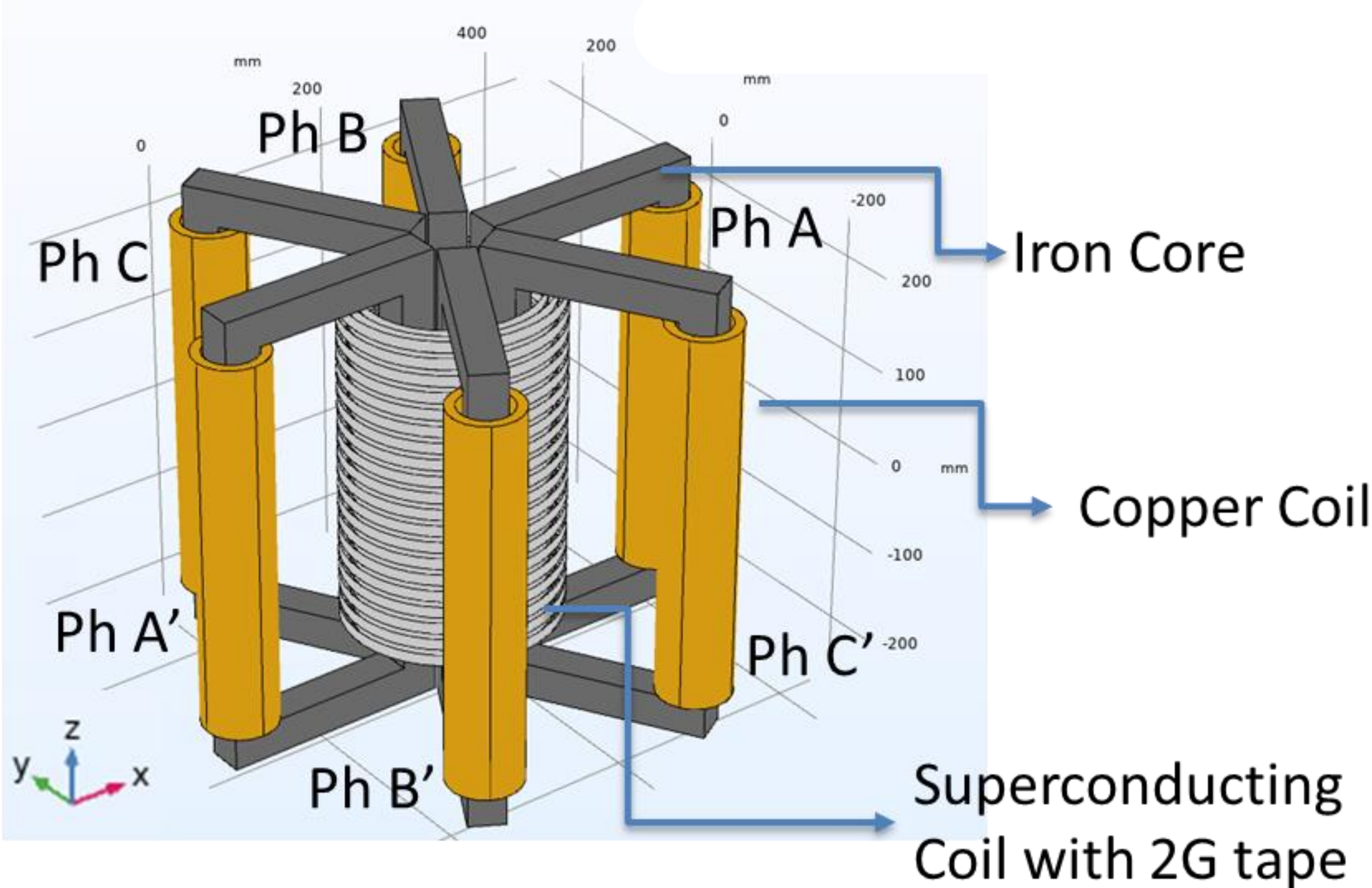
Steady-State Condition



Methodology

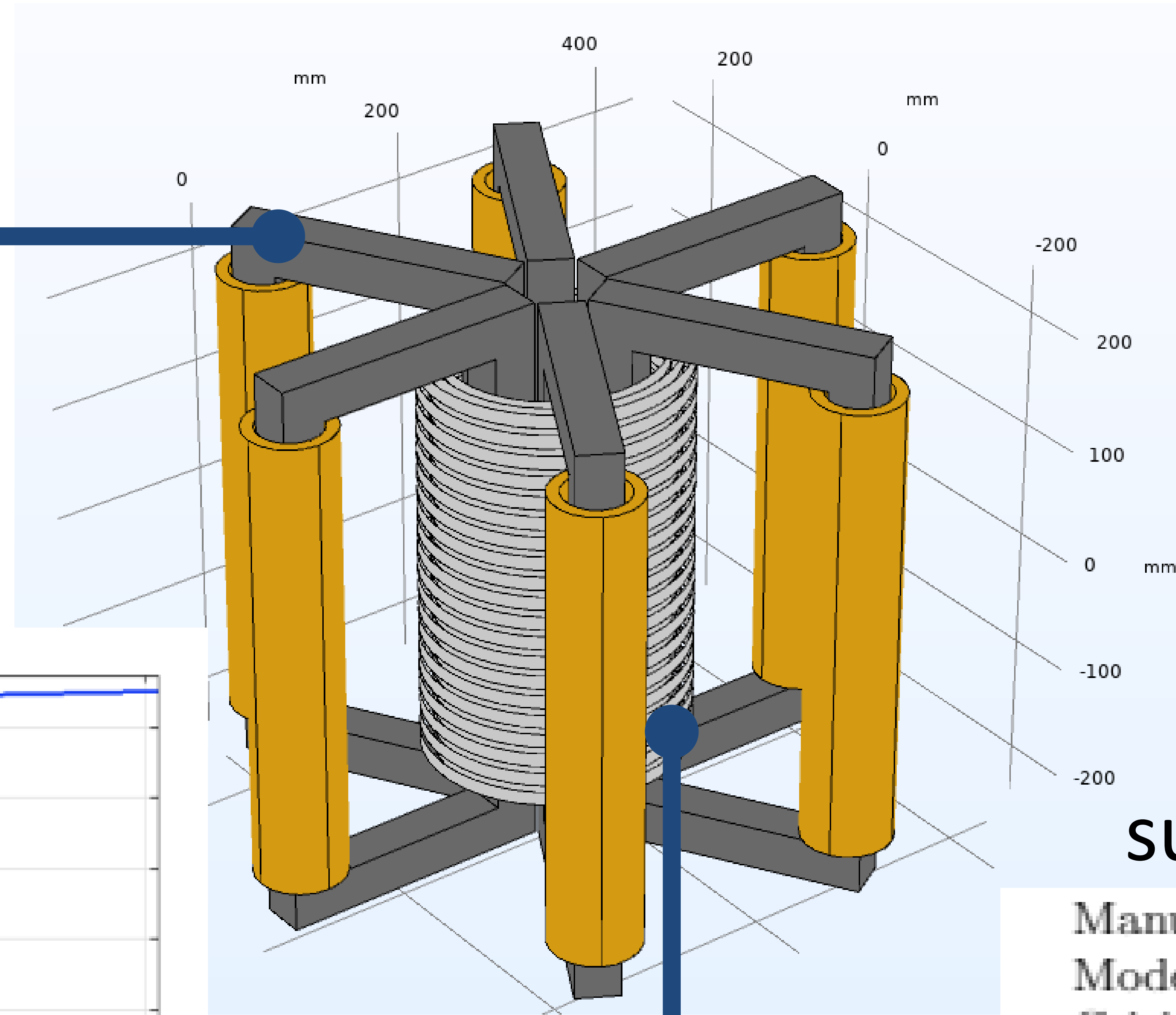
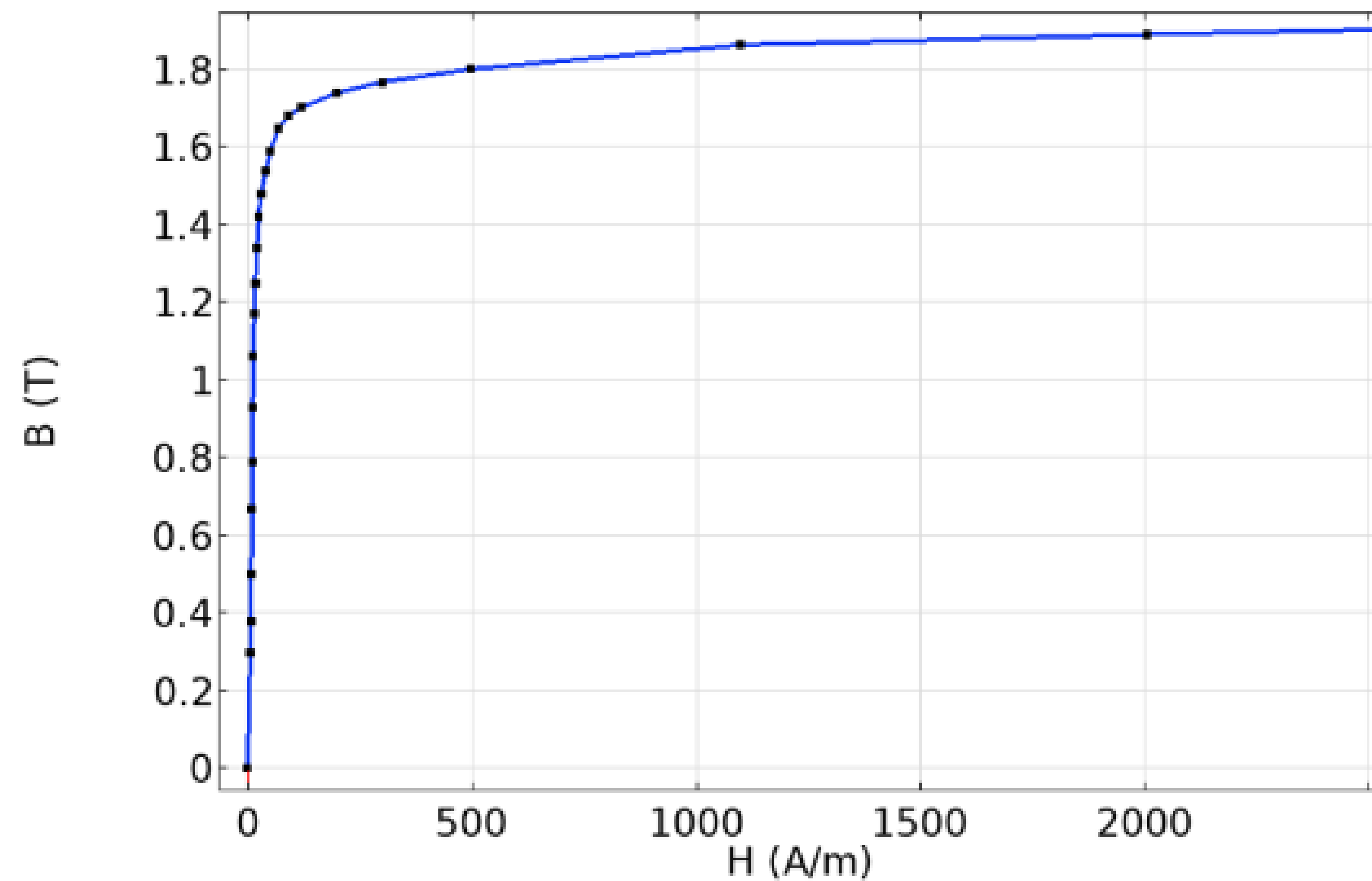


3D SIC-SFCL Model



Methodology

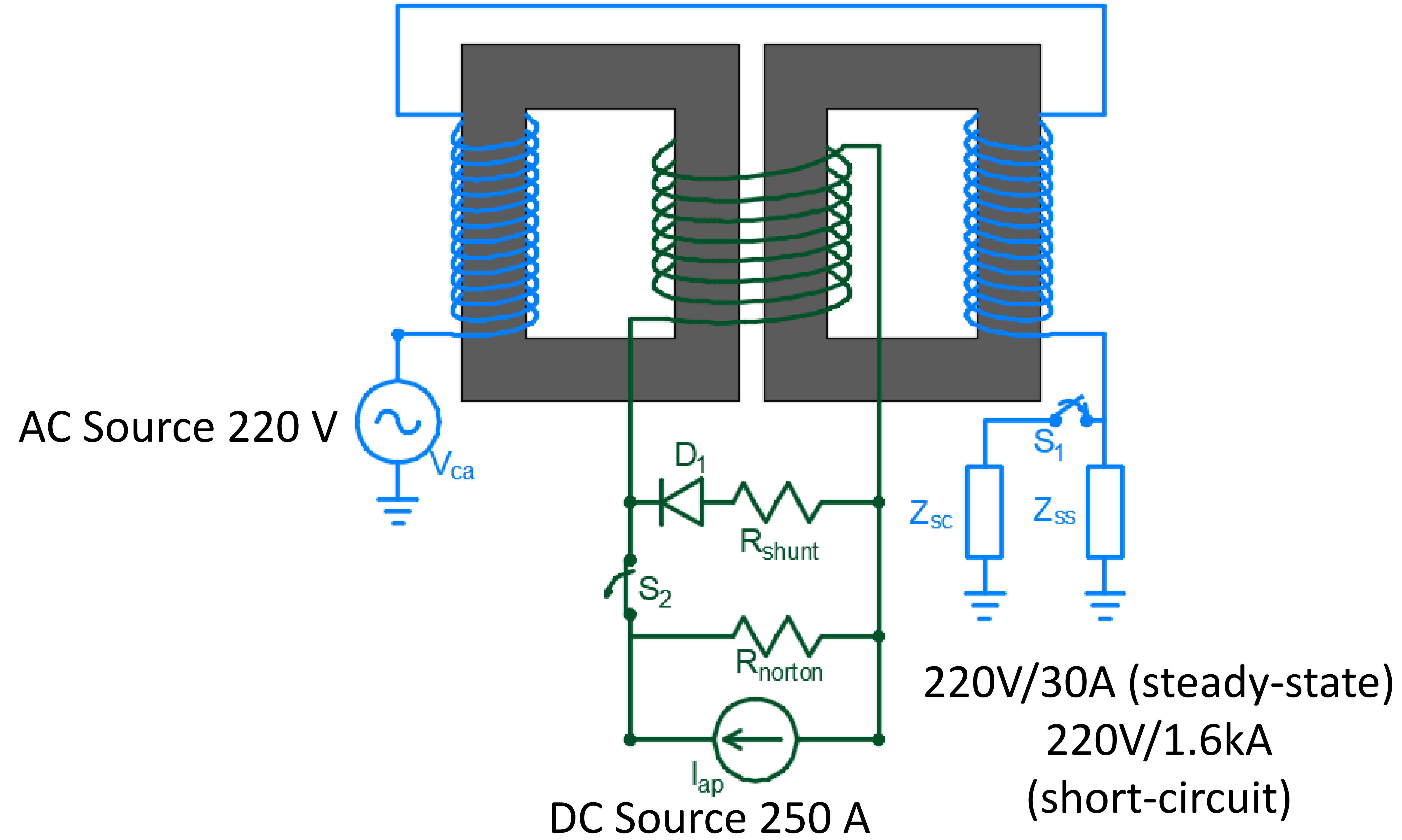
Characterization of the ferromagnetic material



Characterization of the superconducting material

Manufacturer	AMSC
Model	8502
Critical Current @ 77K (I_c [A])	389.75
Width (W_d [mm])	12
Superconductor thickness (t_{sup} [μ m])	1
Tape thickness (t_{tape} [μ m])	200
Anisotropy factor (k) ^a	0.186
B_0 [T] ^a	0.426
α ^a	0.7
Transition index @ 77K (n)	29

Methodology



Methodology

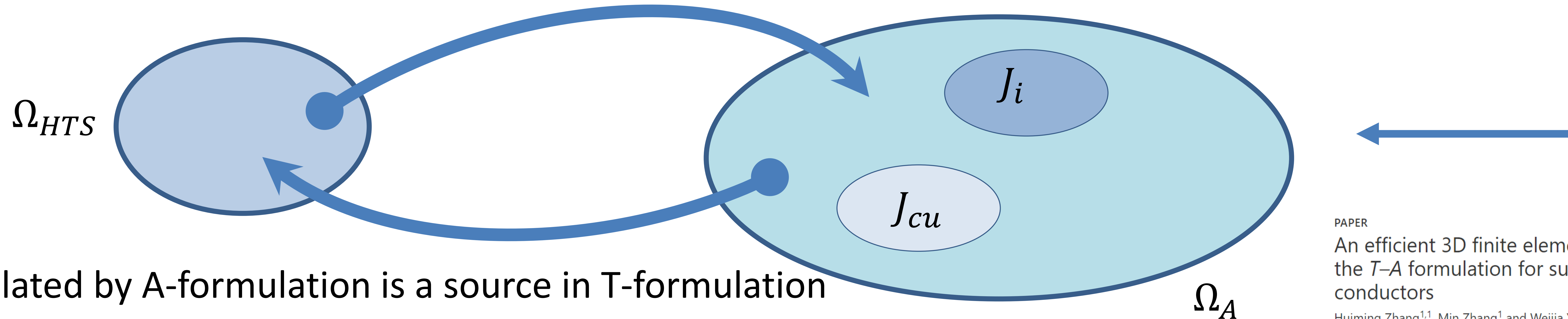
T-Formulation

$$\nabla \times (\rho \nabla \times \mathbf{T}) = -\frac{\partial \mathbf{B}}{\partial t}$$

A-Formulation

$$\nabla \times \left(\frac{1}{\mu} \nabla \times \mathbf{A} \right) = \mathbf{J}_{HTS} + \mathbf{J}_{cu} + \mathbf{J}_i$$

\mathbf{J}_{HTS} calculated by T-formulation is a source in A-formulation



\mathbf{B} calculated by A-formulation is a source in T-formulation

PAPER

An efficient 3D finite element method model based on the T - A formulation for superconducting coated conductors

Huiming Zhang^{1,1}, Min Zhang¹ and Weijia Yuan¹

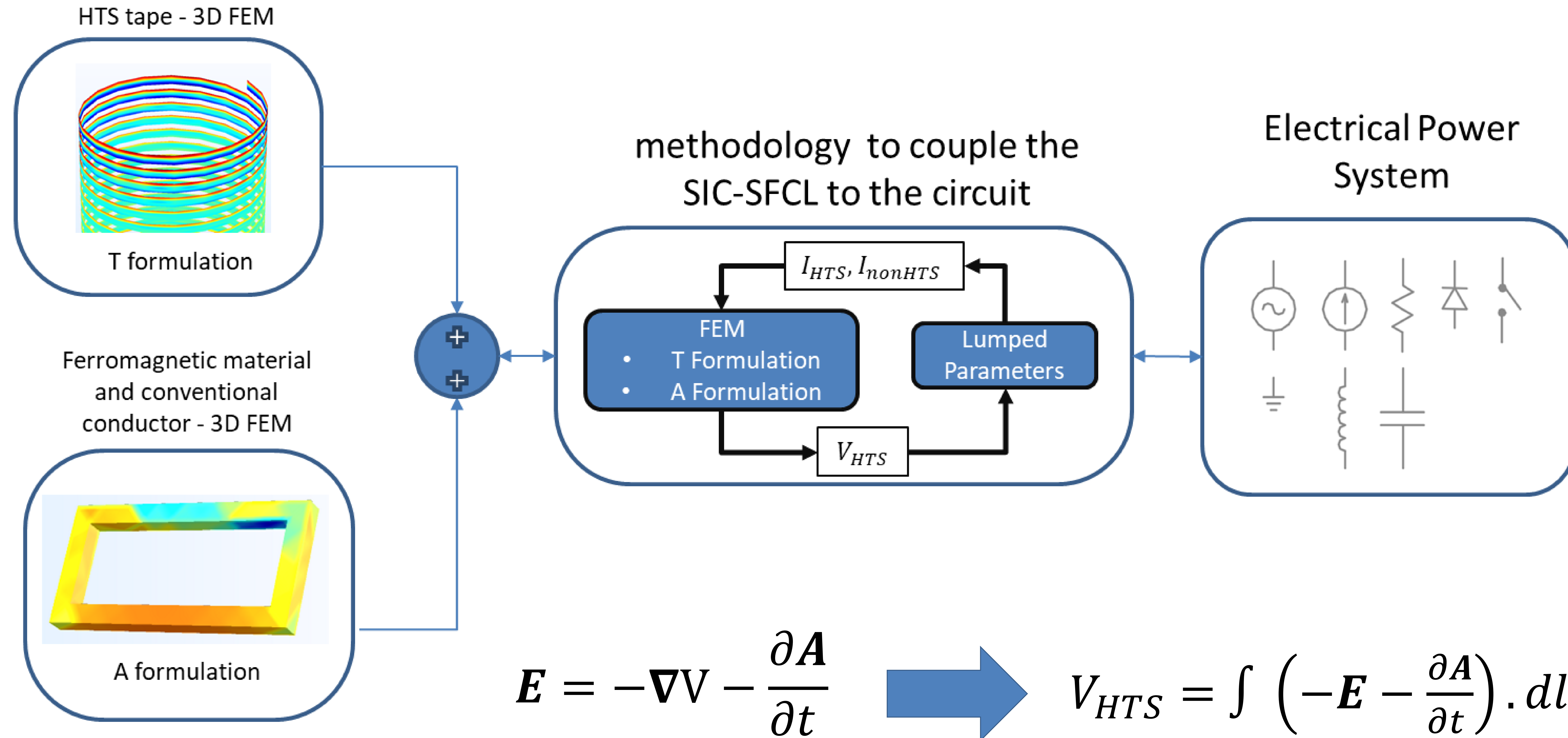
Published 13 December 2016 • © 2016 IOP Publishing Ltd

[Superconductor Science and Technology, Volume 30, Number 2](#)

[Focus on Numerical Modelling of High Temperature Superconductors](#)

Citation Huiming Zhang et al 2017 *Supercond. Sci. Technol.* **30** 024005

Methodology



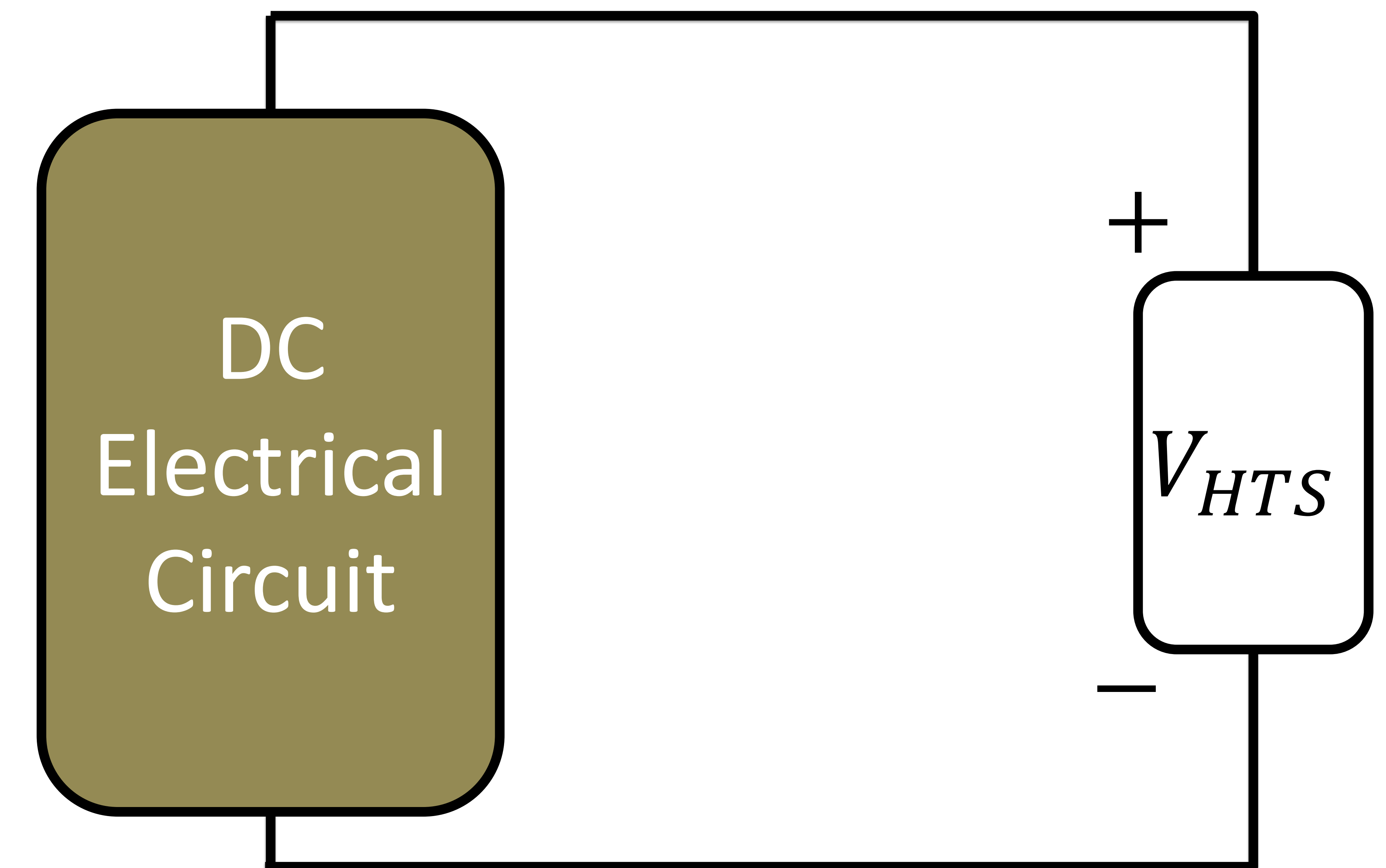
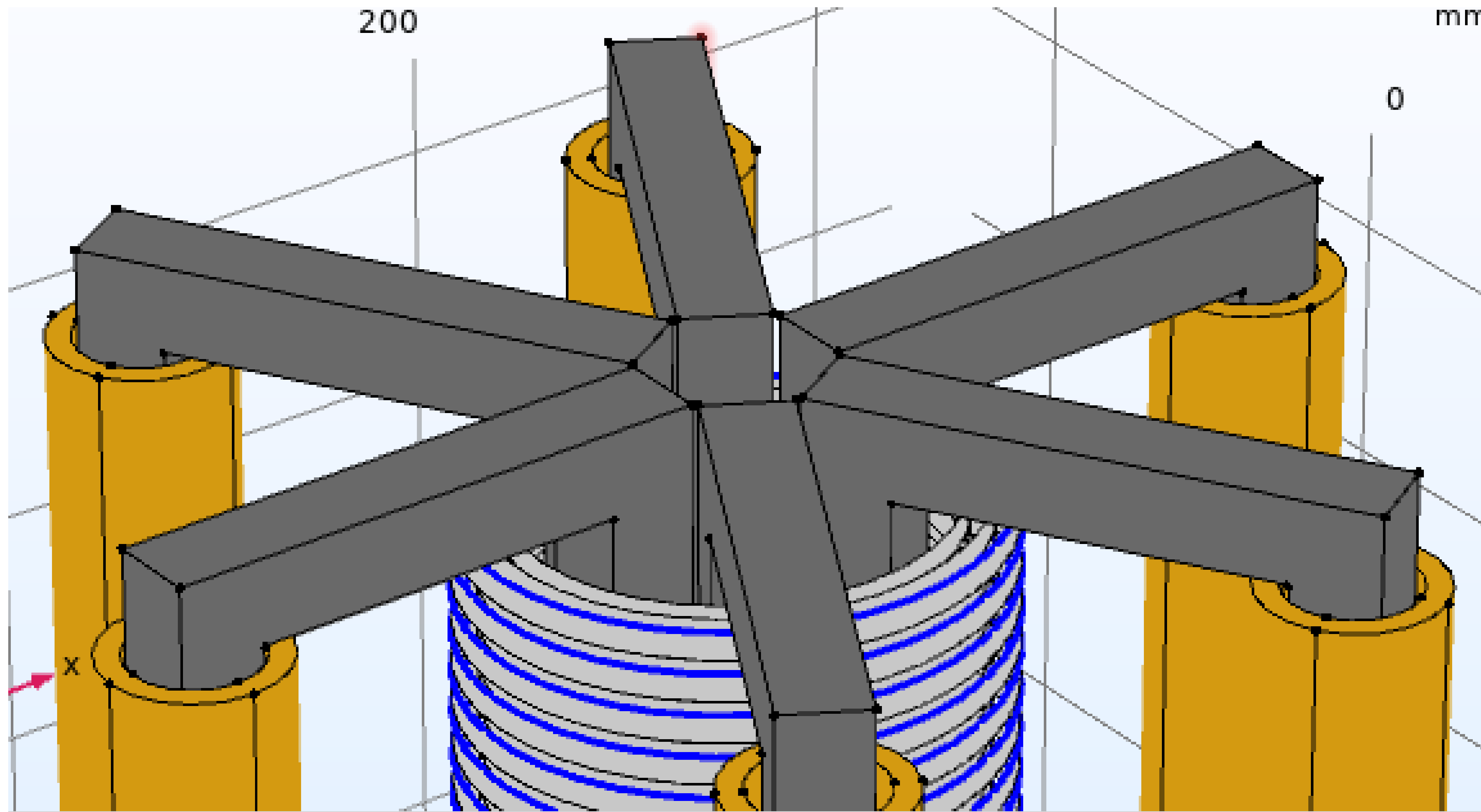
$$\mathbf{E} = -\nabla V - \frac{\partial \mathbf{A}}{\partial t} \quad \longrightarrow \quad V_{HTS} = \int \left(-\mathbf{E} - \frac{\partial \mathbf{A}}{\partial t} \right) \cdot d\mathbf{l}$$

Methodology

$$V_{HTS} = \int \left(-\mathbf{E} - \frac{\partial \mathbf{A}}{\partial t} \right) \cdot d\mathbf{l}$$

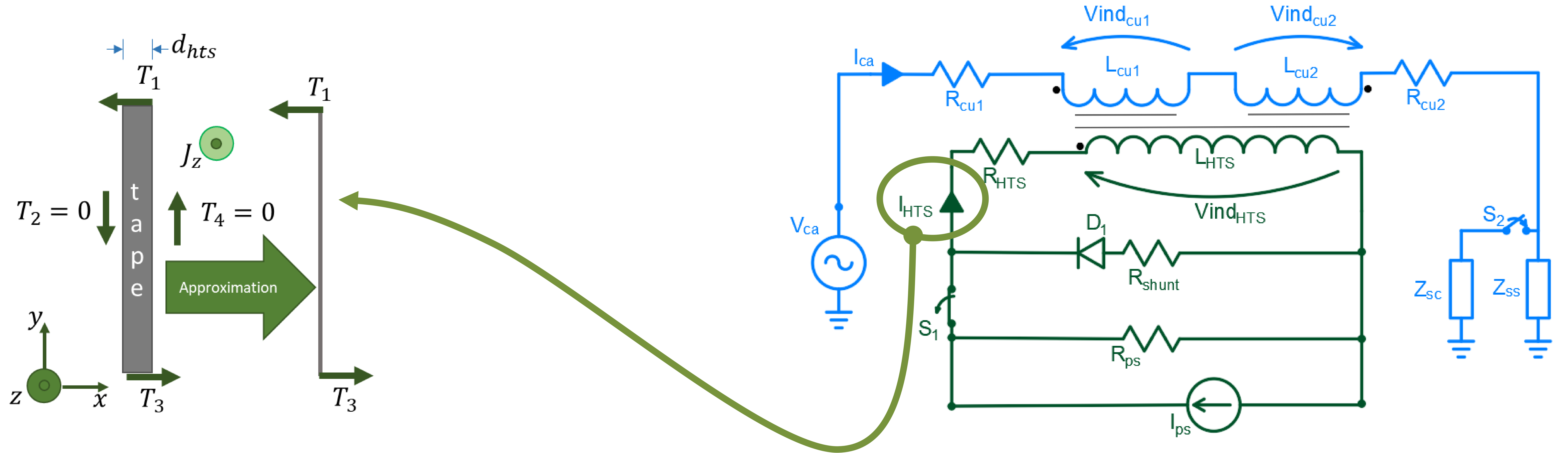
$$\frac{\partial}{\partial t} \mathbf{A} \cdot d\mathbf{l} = \frac{\partial}{\partial t} (A_x \cdot a_x dx + A_y \cdot a_y dy + A_z \cdot a_z dz)$$

$$\mathbf{E} \cdot d\mathbf{l} = E_x \cdot a_x dx + E_y \cdot a_y dy + E_z \cdot a_z dz$$



Methodology

Electrical Schematic of the simulated SIC-SFCL:

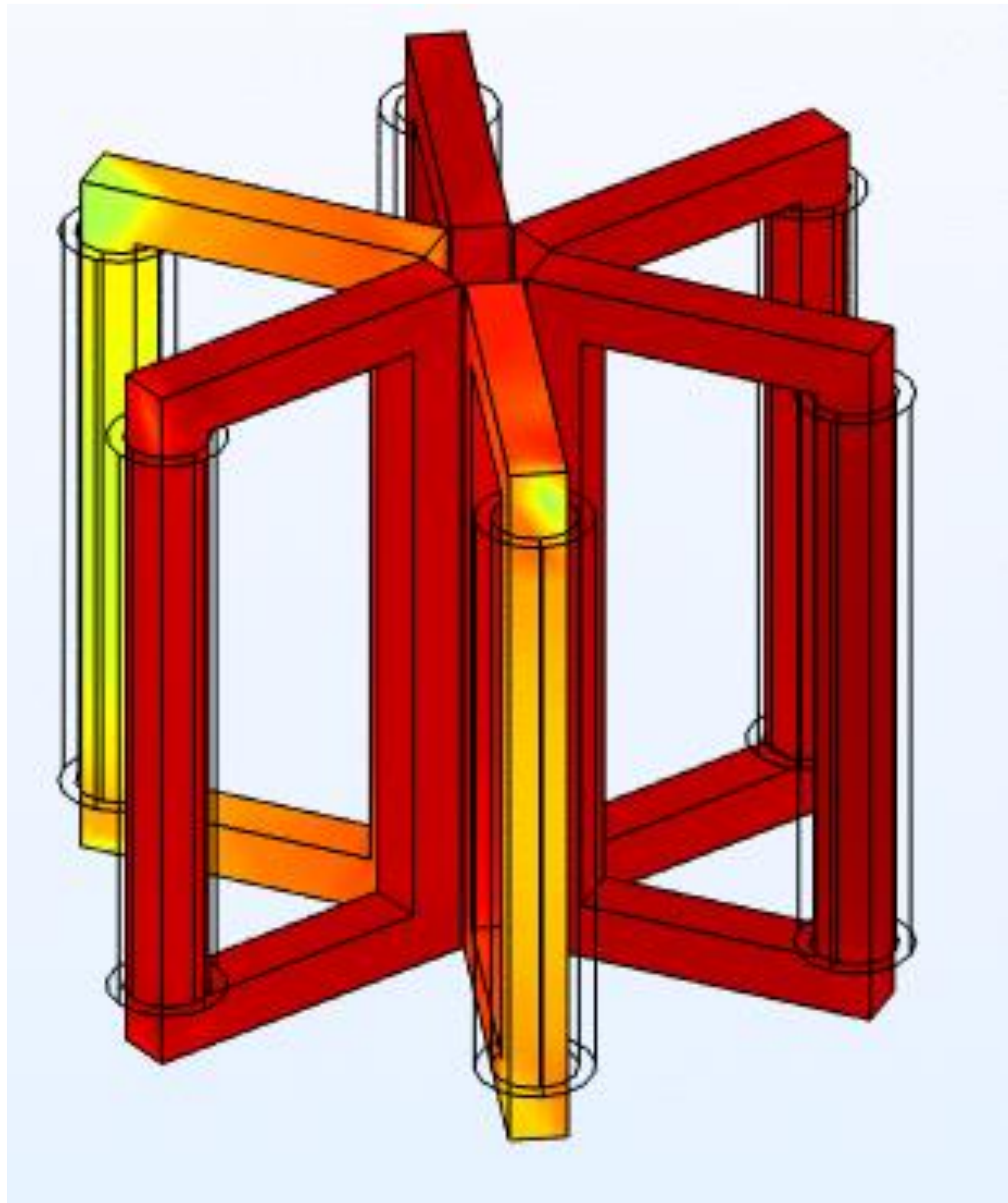


$$T \text{ formulation } (T_1 - T_3) \cdot d_{HTS} = I_{HTS}$$

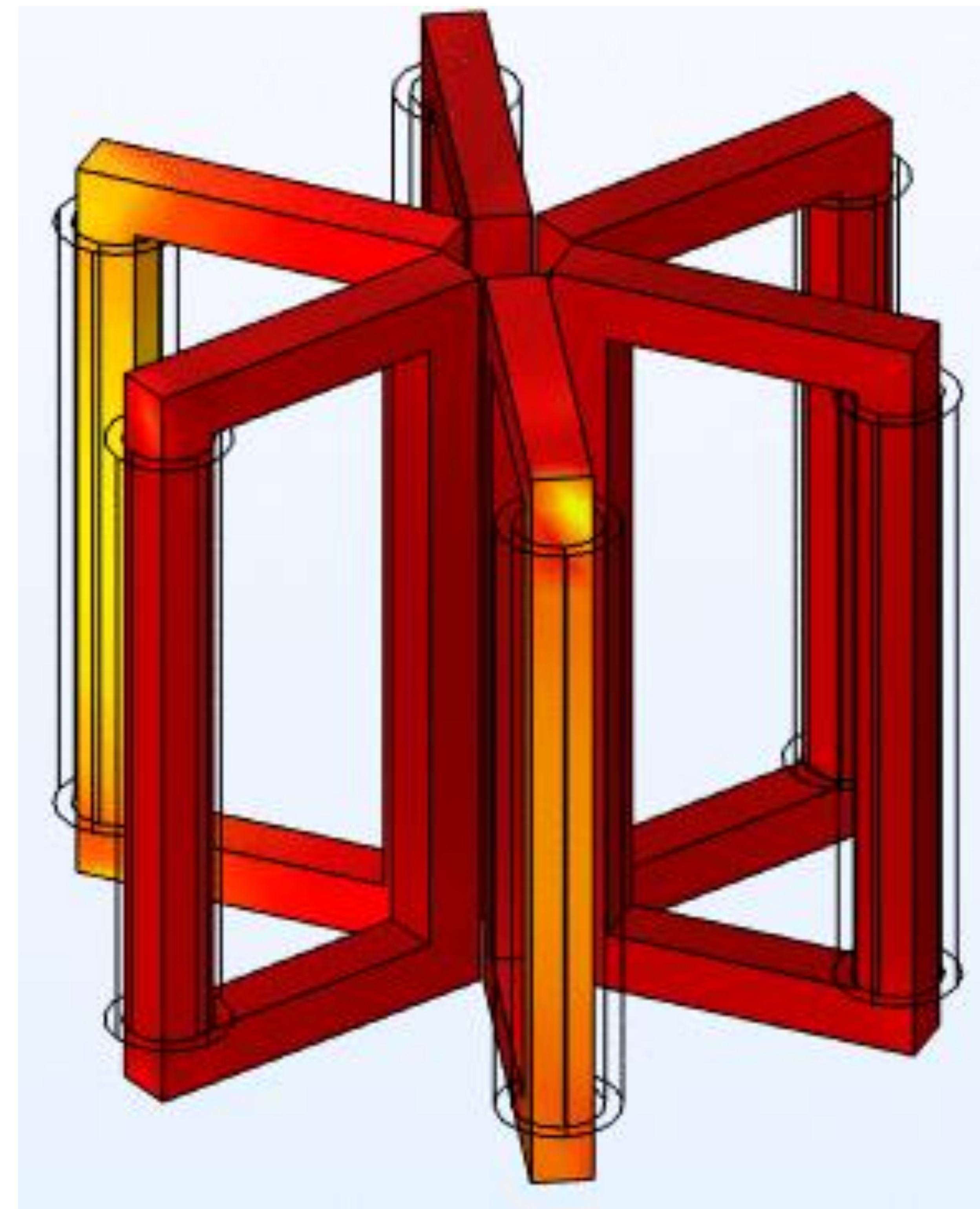
$$A \text{ formulation } n \times (H_1 - H_2) = J_{HTS} \cdot d_{HTS}$$

Results

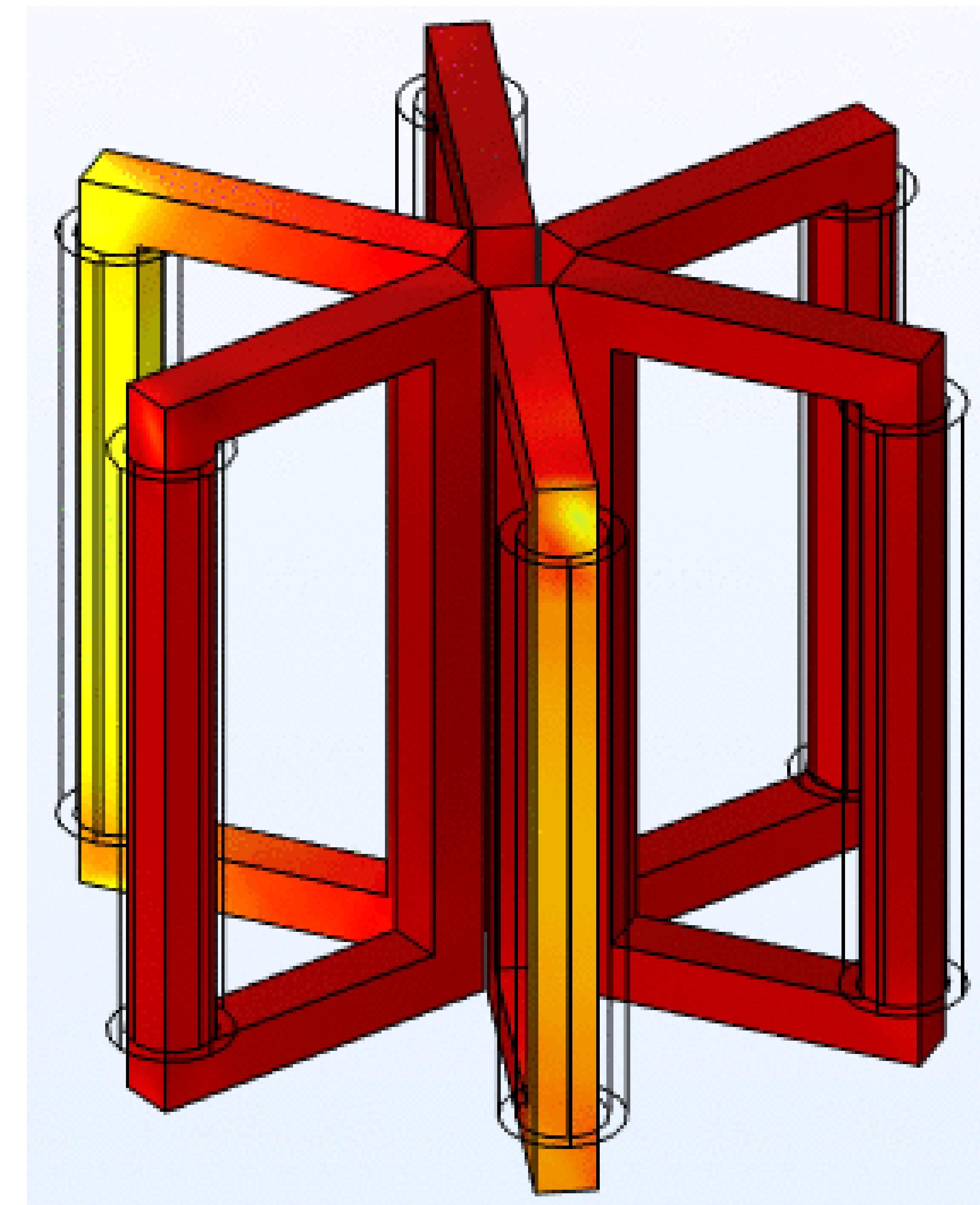
1ϕ



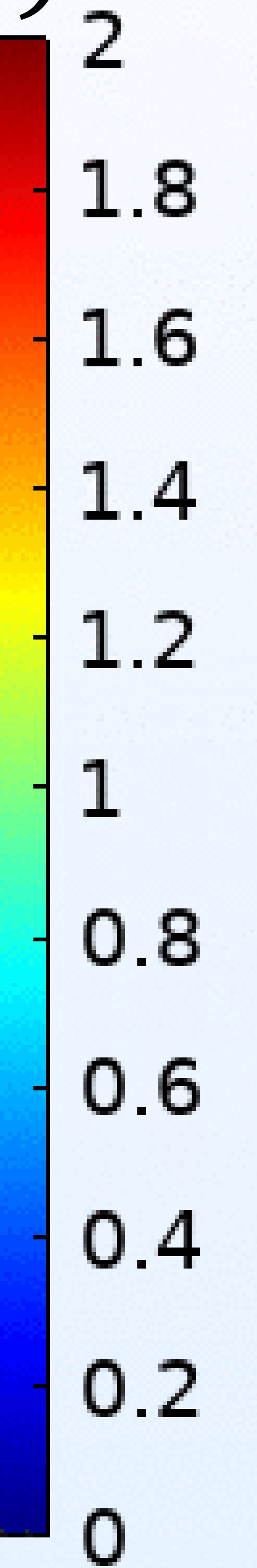
2ϕ



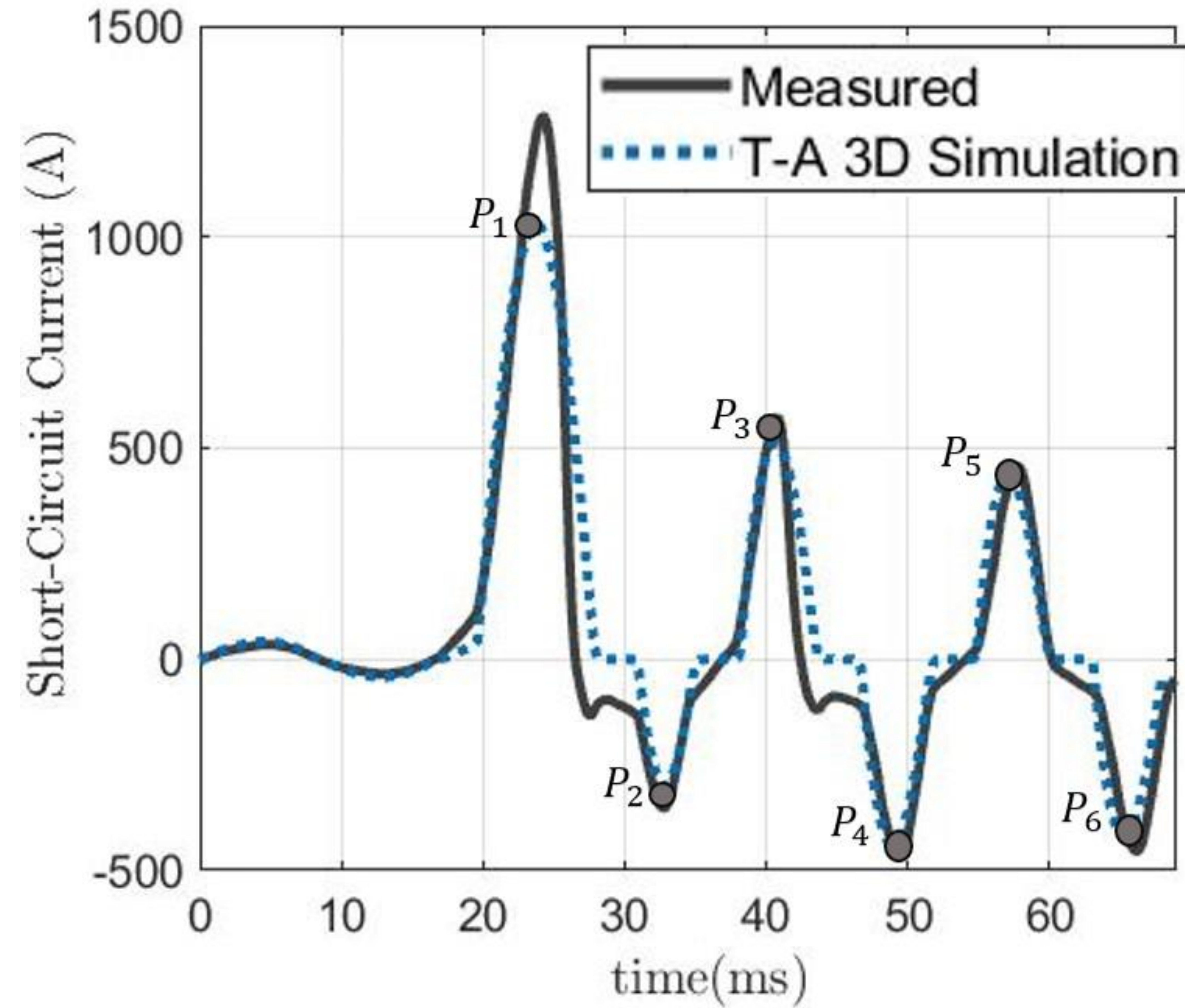
3ϕ



$B(T)$

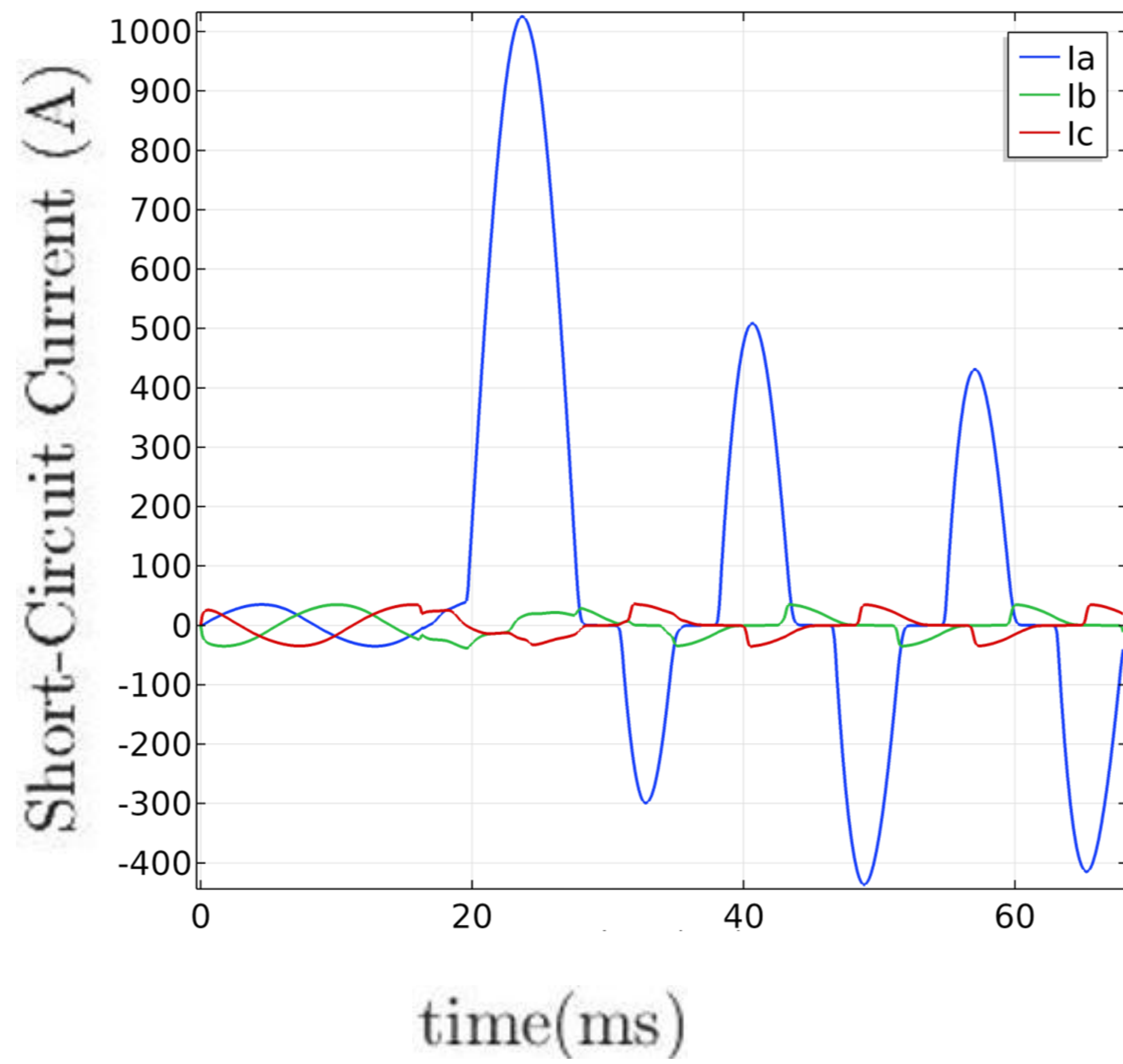


Results

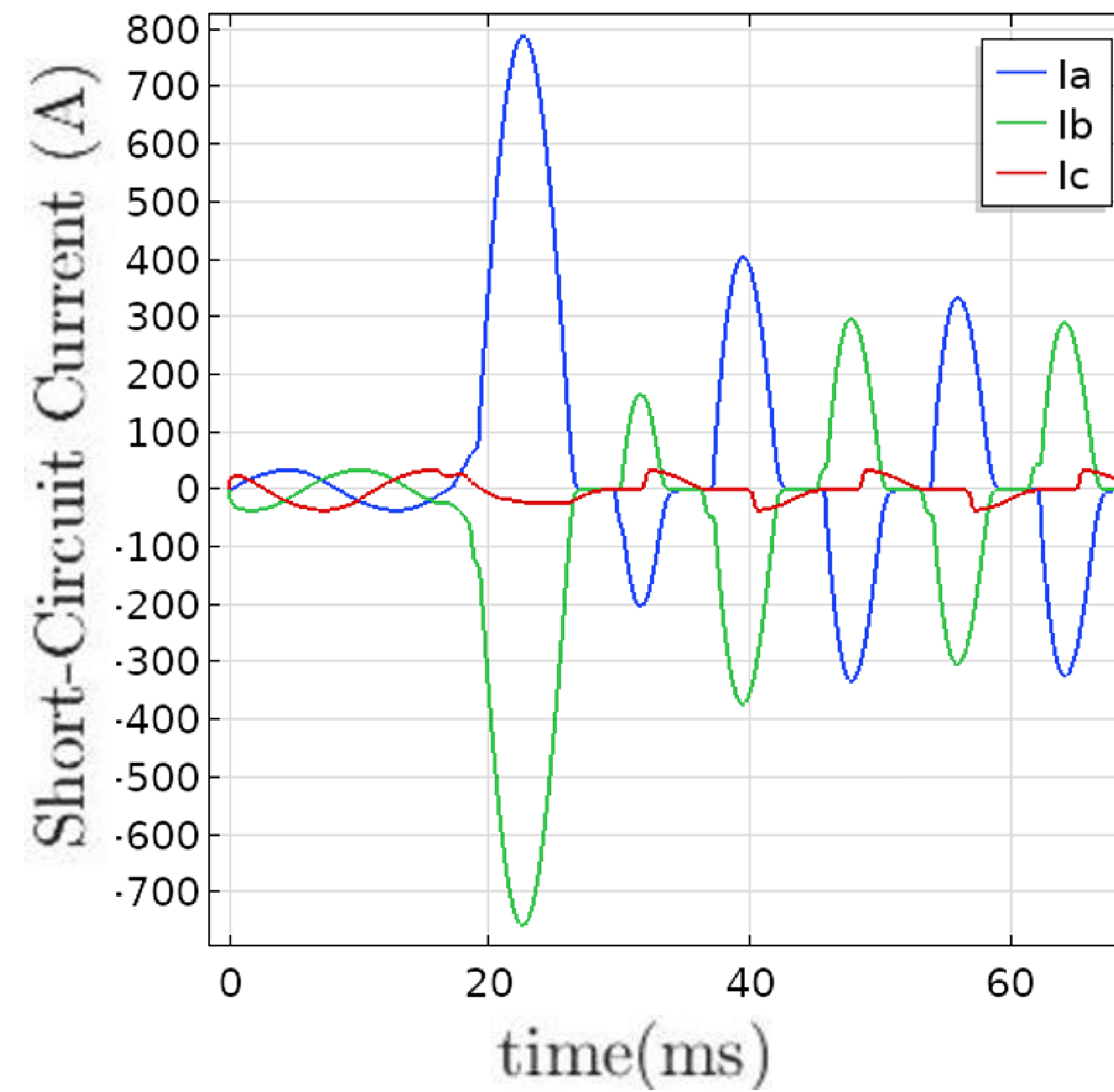


Results

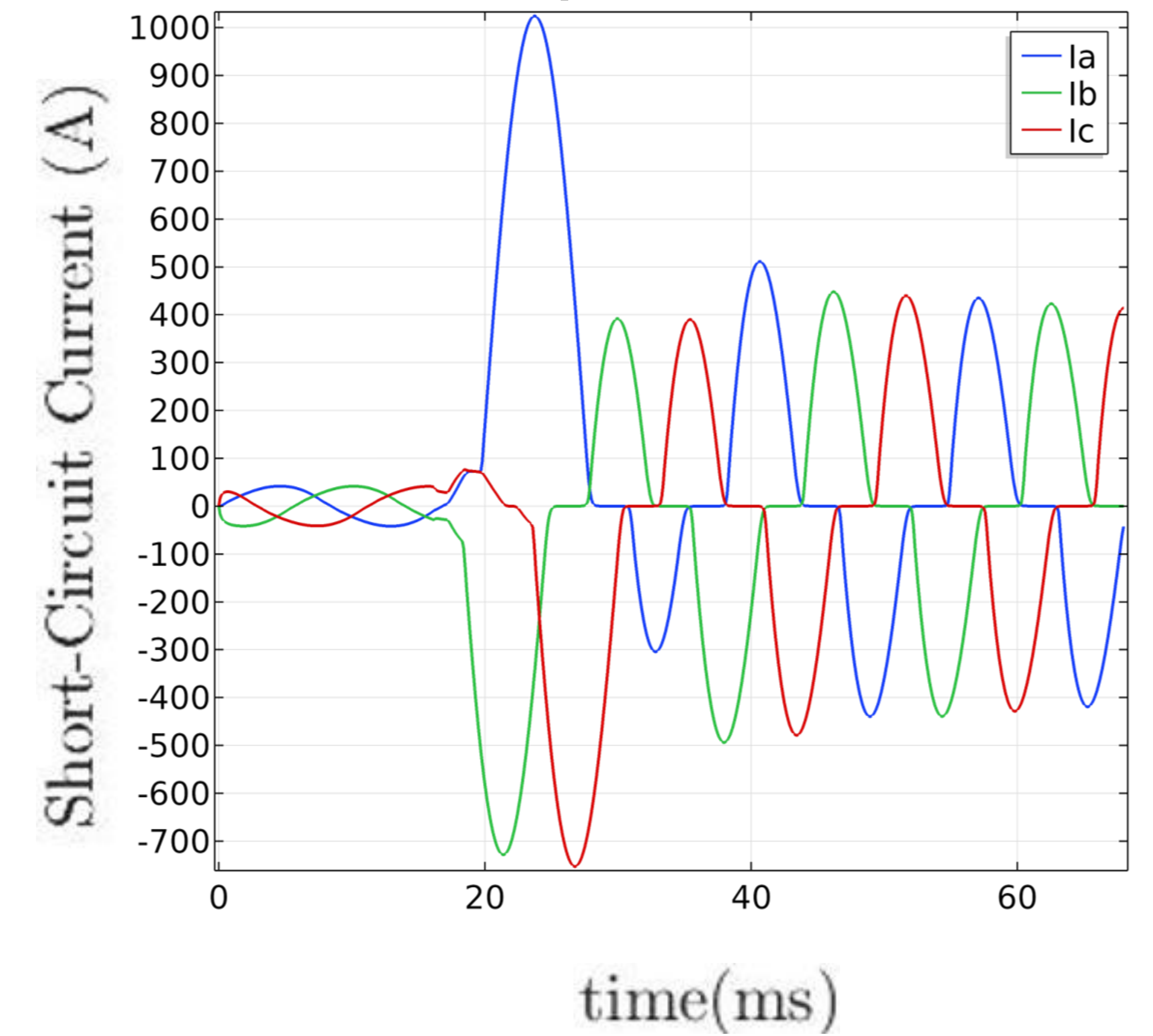
1 ϕ



2 ϕ

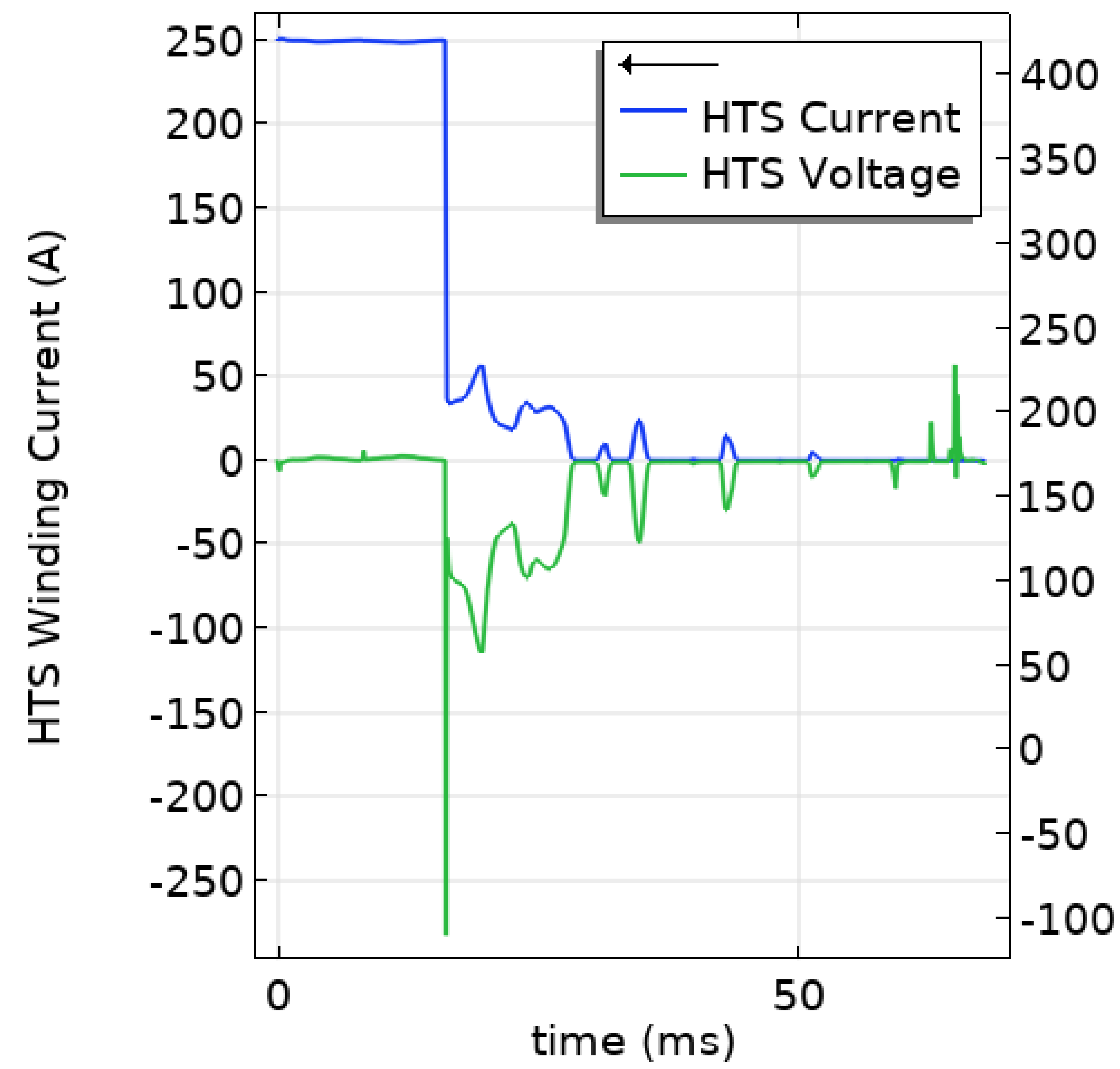


3 ϕ

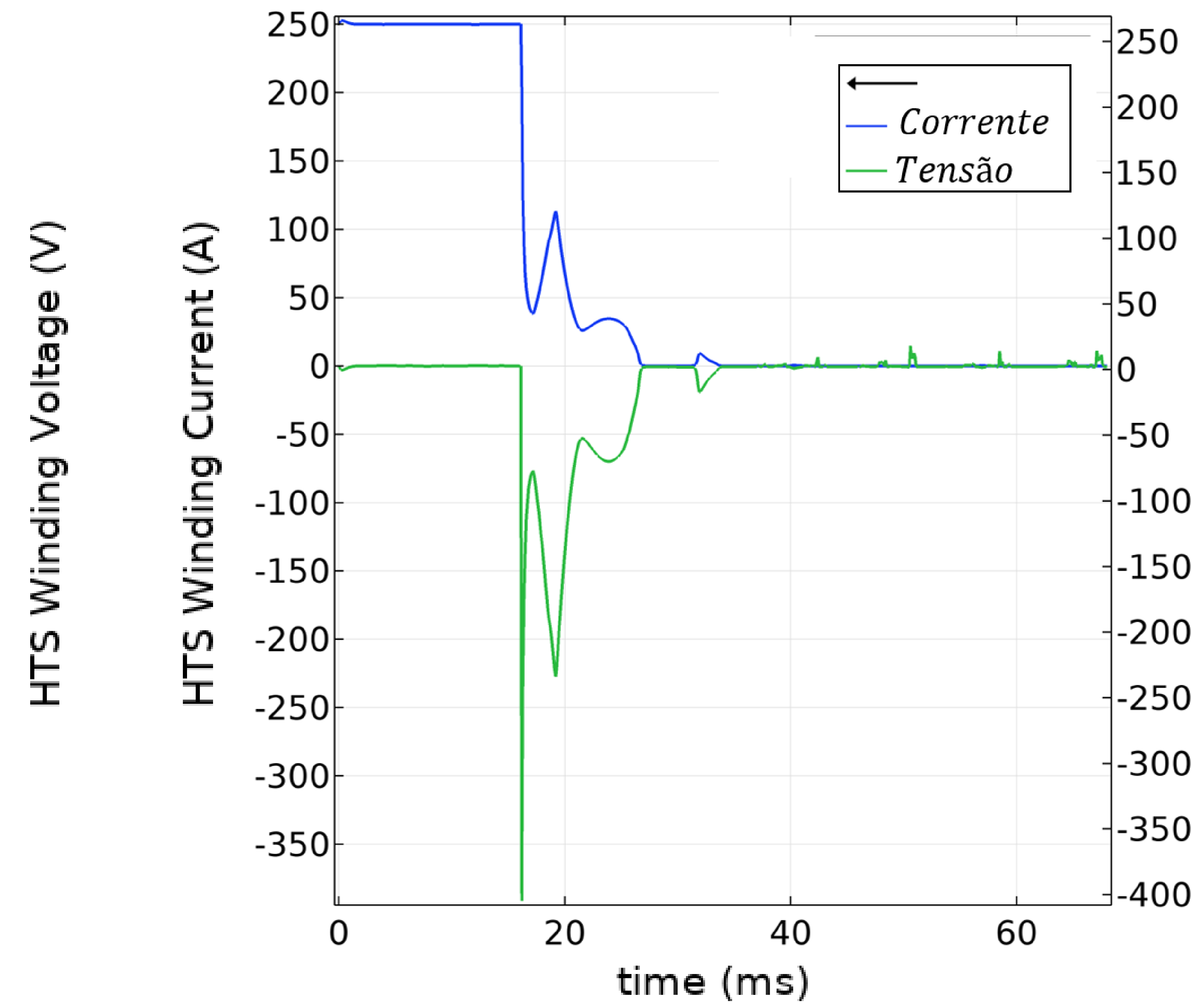


Results

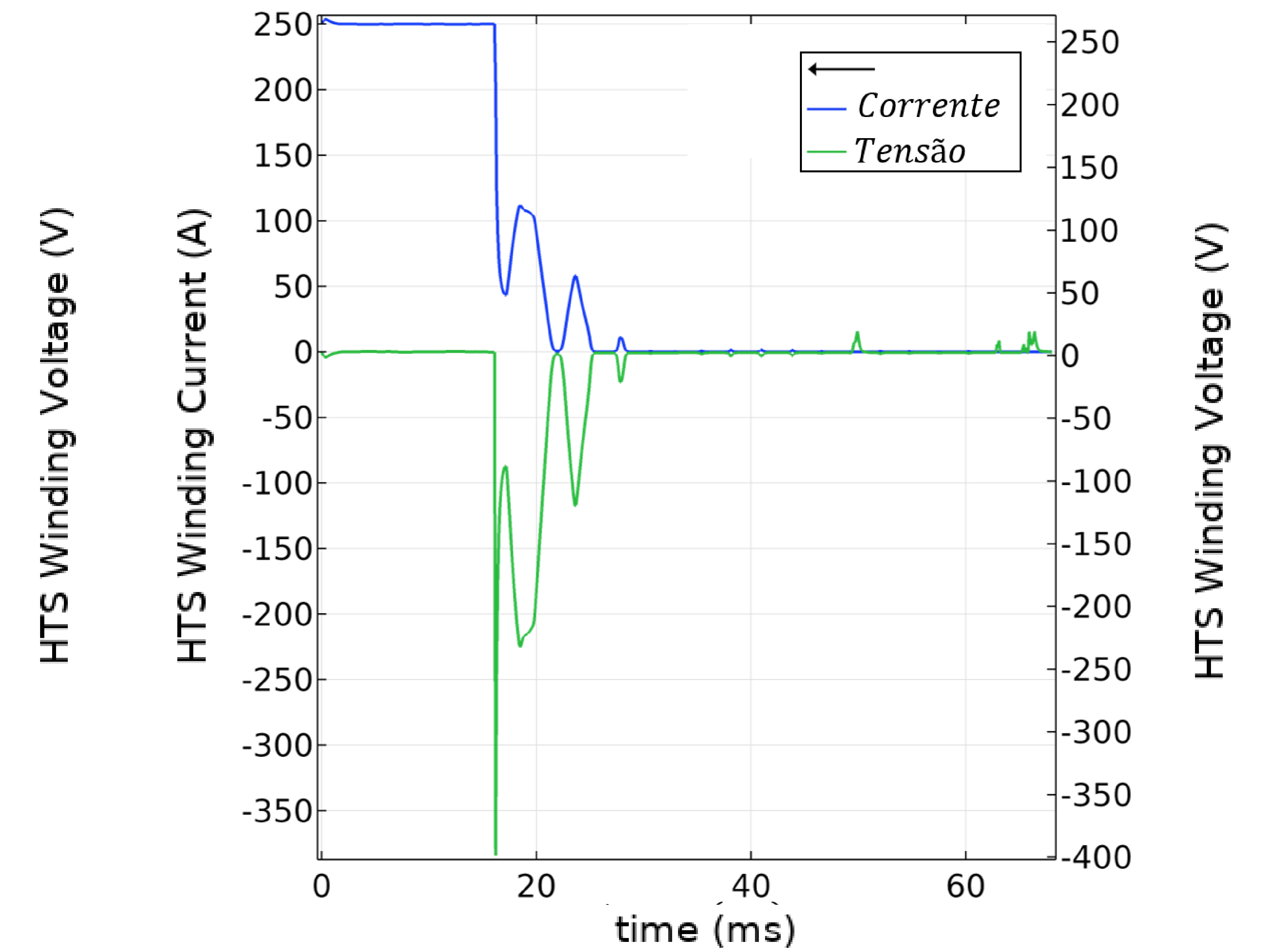
1 ϕ



2 ϕ



3 ϕ



Conclusion

1. The SIC-SFCL was simulated and validated by the experimental tests of the SIC-FCL.
2. Impacts analysis of different short-circuits was performed in order to predict the fault with the highest impact over the DC coil.
3. The highest impact over the DC coil was found in the phase-to-phase short-circuit.
4. Regardless of the kind of short-circuit, all phases are impacted.

Thank you so much

Gabriel dos Santos

e-mail: gdsantos@id.uff.br



ALMA MATER STUDIORUM
UNIVERSITÀ DI BOLOGNA